


<b>Search Notes</b>  	<b>Application/Control No.</b>  10617530	<b>Applicant(s)/Patent Under Reexamination</b>  CHEN ET AL.
	<b>Examiner</b>  Neway, Samuel G	<b>Art Unit</b>  2626

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
EAST: Text Search, PLUS Search	12/21/06	SN
EAST: Inventor, Assignee Search	12/21/06	SN
Consulted: John Peng, QAS, for 101, 112 issues	1/09/07	SN
Consulted: Talivaldis Smits, AU 2626	1/09/07	SN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner